

AO4407A

P-Channel Enhancement Mode Field Effect Transistor



General Description

The AO4407A uses advanced trench technology to provide excellent $R_{\rm DS(ON)}$, and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications. Standard Product AO4407A is Pb-free (meets ROHS & Sony 259 specifications).

Features

 $V_{DS} = -30V$

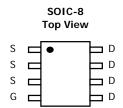
 $I_D = -12A$ $(V_{GS} = -10V)$

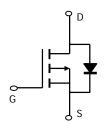
 $R_{DS(ON)}$ < 11m Ω (V_{GS} = -20V)

 $R_{DS(ON)} < 13m\Omega (V_{GS} = -10V)$

 $R_{DS(ON)}$ < 38m Ω (V_{GS} = -10V)

UIS TESTED! RG, CISS, COSS, CRSS TESTED!





Absolute Maximum Ratings T _A =25°C unless otherwise noted							
Parameter		Symbol	10 Sec	Steady State	Units		
Drain-Source Voltage		V_{DS}	-30		V		
Gate-Source Voltage		V_{GS}	±25		V		
Continuous Drain Current ^A	T _A =25°C		-12	-9.2			
	T _A =70°C	I _D	-10	-7.4	۸		
Pulsed Drain Current ^B		I _{DM}	-60		А		
Avalanche Current ^G		I _{AR}	26				
Repetitive avalanche energy L=0.3mH ^G		E _{AR}	101		mJ		
Power Dissipation ^A	T _A =25°C	-P _D	3.1	1.7	W		
	T _A =70°C		2.0	1.1	VV		
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150		°C		

Thermal Characteristics							
Parameter	Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient A	t ≤ 10s		32	40	°C/W		
Maximum Junction-to-Ambient A	Steady State	$R_{ hetaJA}$	60	75	°C/W		
Maximum Junction-to-Lead ^C	Steady State	$R_{ hetaJL}$	17	24	°C/W		

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units			
STATIC PARAMETERS									
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V			
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -30V, V_{GS} = 0V$			-10	μА			
		$T_J = 55^{\circ}C$			-50				
I_{GSS}	Gate-Body leakage current	$V_{DS} = 0V$, $V_{GS} = \pm 25V$			±100	nA			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS} I_D = -250 \mu A$	-1.7	-2.3	-3	V			
$I_{D(ON)}$	On state drain current	$V_{GS} = -10V, V_{DS} = -5V$	-60			Α			
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -20V, I_D = -12A$		8.5	11				
		T _J =125°C		11.5	15	mΩ			
	Static Dialii-Source Off-Resistance	$V_{GS} = -10V, I_D = -12A$		10	13	1112.2			
		$V_{GS} = -5V, I_D = -10A$		27	38				
g _{FS}	Forward Transconductance	$V_{DS} = -5V, I_{D} = -10A$		21		S			
V_{SD}	Diode Forward Voltage	$I_S = -1A, V_{GS} = 0V$		-0.7	-1	V			
I _S	Maximum Body-Diode Continuous Curr			-3	Α				
DYNAMIC	PARAMETERS								
C _{iss}	Input Capacitance			2060	2600	pF			
Coss	Output Capacitance	V_{GS} =0V, V_{DS} =-15V, f=1MHz		370		pF			
C _{rss}	Reverse Transfer Capacitance			295		pF			
R_g	Gate resistance	V_{GS} =0V, V_{DS} =0V, f=1MHz		2.4	3.6	Ω			
SWITCHI	NG PARAMETERS								
Q_g	Total Gate Charge			30	39	nC			
Q_{gs}	Gate Source Charge	V_{GS} =-10V, V_{DS} =-15V, I_{D} =-12A		4.6		nC			
Q_{gd}	Gate Drain Charge			10		nC			
$t_{D(on)}$	Turn-On DelayTime			11		ns			
t _r	Turn-On Rise Time	V_{GS} =-10V, V_{DS} =-15V, R_L =1.25 Ω ,		9.4		ns			
$t_{D(off)}$	Turn-Off DelayTime	R_{GEN} =3 Ω		24		ns			
t _f	Turn-Off Fall Time]		12		ns			
t _{rr}	Body Diode Reverse Recovery Time	I _F =-12A, dI/dt=100A/μs		30	40	ns			
Q_{rr}	Body Diode Reverse Recovery Charge	I _F =-12A, dI/dt=100A/μs		22		nC			

A: The value of R $_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T $_A$ = 25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating.

- B: Repetitive rating, pulse width limited by junction temperature.
- C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.
- D. The static characteristics in Figures 1 to 6 are obtained using < 300 μs pulses, duty cycle 0.5% max.
- E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T $_A$ =25°C. The SOA curve provides a single pulse rating.
- F. The current rating is based on the $t \leqslant 10 s$ thermal resistance rating.
- G. E_{AR} and I_{AR} ratings are based on low frequency and duty cycles to keep T_i=25C.

Rev3: Jan 2008

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

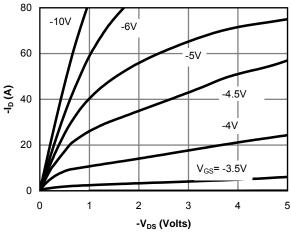


Figure 1: On-Region Characteristics

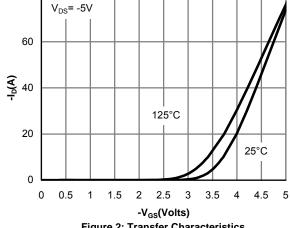


Figure 2: Transfer Characteristics

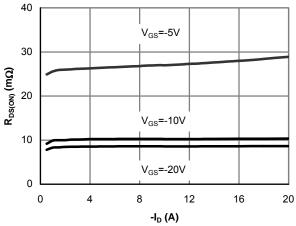


Figure 3: On-Resistance vs. Drain Current and **Gate Voltage**

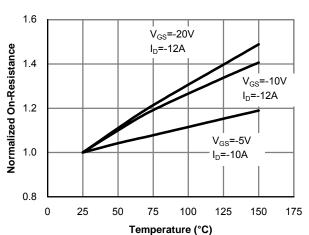


Figure 4: On-Resistance vs. Junction Temperature

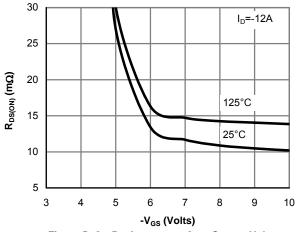


Figure 5: On-Resistance vs. Gate-Source Voltage

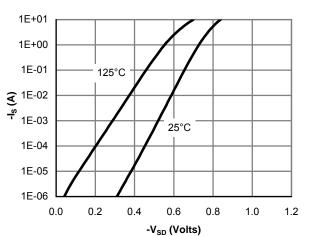
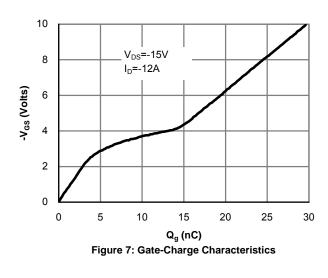


Figure 6: Body-Diode Characteristics

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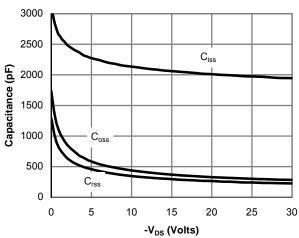


Figure 8: Capacitance Characteristics

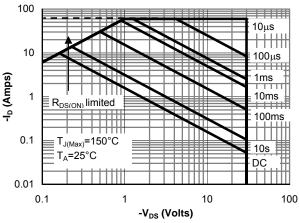


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

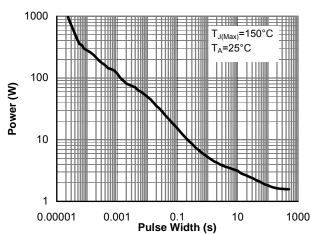


Figure 10: Single Pulse Power Rating Junctionto-Ambient (Note E)

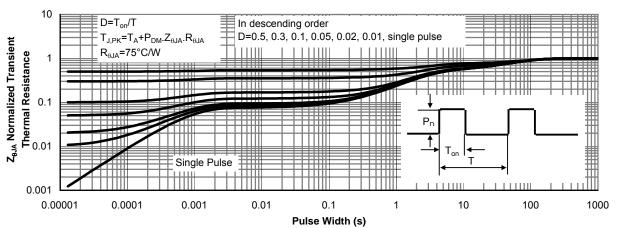


Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)

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